

ABSTRACT OF THE DISCLOSURE

In a test method of a memory IC function, memory ICs of different types are prepared after a memory tester is prepared. The data related to each test method of these memory ICs is transmitted to the memory tester. Further, after a random number is generated, a test of a predetermined memory IC is executed in reply to the generated random number. It is checked whether the tests of all the memory ICs are finished or not: and the generation of the random number and the execution of the test are repeated when they are not finished, while the processing is finished when they are finished.